

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination FUJIWARA ET AL.	
		Examiner Franklin S. Andramuno	Art Unit 2623	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,169,543	01-2001	Wehmeyer, Keith Reynolds	725/47
*	B	US-2003/0172382	09-2003	Kim, Kyung-ah	725/53
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
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